

PRODUCT/PROCESS CHANGE NOTIFICATION PCN 10546 – Additional information

ASE Kaohsiung (Taiwan) additional source for LQFP 7x7 STM32F0-F1-F3 listed products

MDG - Microcontrollers Division (MCD)

What are the changes?

Changes are described in the below table:

	Existing			Added
	back-end sites			back-end site
Assembly site	Stats ChipPAC JSCC	ST	Amkor ATP	ASE
	Jiangyin China	Muar Malaysia	Philippines	Kaohsiung Taiwan
Leadframe	Copper Frame	Pre Plated Frame	Copper Frame	Copper Frame
	Spot Ag		Spot Ag	Spot Ag
Leadfinishing (1)	Pure Tin (e3)	Ni Pd Au (e4)	Pure Tin (e3)	Pure Tin (e3)
Resin (2)	Sumitomo	Sumitomo	Sumitomo	Sumitomo
	G631SHQ	G700LS	G631HQ	EME-G631SH
Glue	Ablestik	Hitachi	Evertech	Sumitomo
	3230	EN4900	AP4200	CRM 1076WA
Wire	Silver 96.5% 0.8mil	Gold 0.8mil	Gold 0.8mil	Gold 0.8mil
		Silver 96.5% 0.8mil		
Enhanced	2 digits	2 digits	No digit	2 digits
traceability				
in marking				

- (1) Lead color and surface finish change depending on leadfinishing.
- (2) Package darkness changes depending on molding compound.

How can the change be seen?

The standard marking is:

e4
PPLLL WX

PP code indicates the assembly traceability plant code.

Please refer to the <u>DataSheet</u> for marking details.

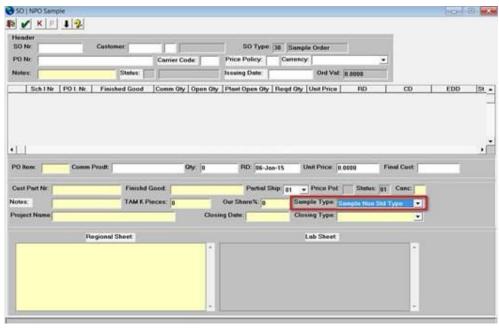
The marking is changing as follows:

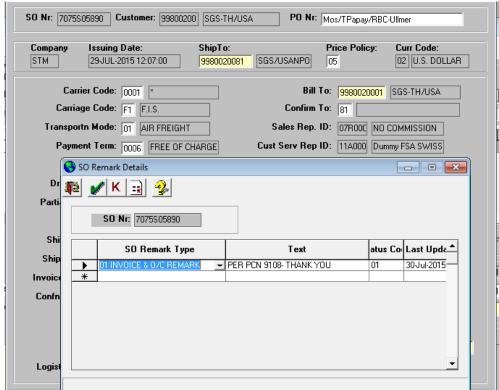
	Existing	Additional		
PP code	Fab	PP code	Fab	
GQ & GH	Stats ChipPAC China	AA	ASE Kaohsiung Taiwan	
9H	ST Muar Malaysia			
7B	Amkor Philippines			

How to order samples?

For all sample request linked to this PCN, please:

- request sample(s) through Notice tool, indicating a single Commercial Product for each request.
- insert "PCN 10546" into the remarks of your order.
- place **non standard** sample order using the following field in your system.







RER1717 for PCN 10546 ASEKH Taiwan additional source for LQFP 7x7 STM32F0-F1-F3

Reliability Evaluation Plan

Dec 15th, 2017

MDG MCD Quality & Reliability Department



RER1717 ASEKH Taiwan additional source for LQFP 7x7 STM32F0-F1-F3 Package Test Vehicles

Package line	Assembly Line	Package	Device (Partial RawLine Code)	Diffusion Process	Number of Reliability Lots
LQFP	LQFP 7*7	48L	STM32(5B*410)	TSMC0.18μm	3
LQFP	LQFP 7*7	32L	STM32(5V*444)	TSMC0.18μm	1

Note: Test vehicles are selected by Change Review Board based on key parameters such as die size and volumes allowing to qualify the entire product family in LQFP using same TSMC0.18 diffusion process



RER1717 ASEKH Taiwan additional source for LQFP 7x7 STM32F0-F1-F3 Package Reliability Trials

Reliability Trial & Standard		Test Conditions	Pass Criteria	Unit per Lot	Lot qty
PC	Pre Conditioning: Moisture Sensitivity Jedec Level 3 J-STD-020/ JESD22-A113	Bake (125°C / 24 hrs) Soak (30°C / 60% RH / 192 hrs) for level 3 Convection reflow: 3 passes	3 passes MSL3	308	3 for 410 (LQFP48L) 1 for 444 (LQFP32L)
AC or Uhast(*)	Autoclave JESD22 A102 or UnBiased Highly Accelerated Temperature and Humidity Stress JESD22 A118	121°C, 100% RH, 2 Atm 130°C, 85%RH, 2 atm	96h	77	3 for 410 (LQFP48L)
TC(*)	Thermal Cycling JESD22 A104	-50°C, +150°C Or equivalent -65°C +150°C	1000Cy 500Cy	77	3 for 410 (LQFP48L)
HAST(*)	Biased Highly Accelerated temperature & humidity stress JESD22 A110	110°C, 1.2 atm , 85% RH bias	264h	25	3 for 410 (LQFP48L)
HTSL	High Temperature Storage Life JESD22 A103	150°C- no bias	1000h	77	3 for 410 (LQFP48L)
Construction analysis	JESD 22B102 JESDB100/B108	including Solderability, Physical dimensions	15 10		1 per package
ESD	ESD Charge Device Model ANSI/ESD STM5.3.1	Aligned with device datasheet	250V to 500V	3	1 per device



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